



Invitation to 4th CIA-CT Conference on "Applications of Computed Tomography in Industrial Production"

June 19, 2013, 10:00-16:30
University of Copenhagen
Niels Bohr Institute, Auditorium M
Blegdamsvej 21, Copenhagen, Denmark

The conference provides the latest update on the use of CT scanning for measurement, quality assurance and product development in industrial production. The conference program includes 10 invited presentations by international experts and industrial users of CT scanning.

The conference is an activity within the Danish innovation consortium "Center for Industrial Application of CT scanning - CIA-CT" representing a major European initiative in the field of Industrial Computed Tomography. Information concerning the consortium, which is supported by the Danish Council for Technology and Innovation, is available from the website: www.cia-ct.mek.dtu.dk.

Registration to the conference by June 12, 2013 at the following link:

<http://indico.conferences.dtu.dk/conferenceDisplay.py?confId=153>

Conference fee: DKK 1850 - EUR 250

The fee includes conference material, lunch and coffee breaks. The fee is tax-free.

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We look forward to seeing you at the conference!

www.ku.dk

www.dtu.dk

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9.30-10.00	Registration and coffee Introduction	
10.00-10.10	Welcome	Robert K. Feidenhans'l, KU-NBI, Denmark
10.10-10.30	"Centre for Industrial Application of CT scanning (CIA-CT) – four years of results"	Leonardo De Chiffre, DTU Mekanik, Denmark
10.30-10.50	Break Session on "Physics of Computed Tomography"	
10.50-11.10	"Principles of Computed Tomography" 1	Robert K. Feidenhans'l, KU-NBI, Denmark
11.10-11.30	"Image quality enhancement in Computed 2 Tomography"	Jochen Hiller, Carl Zeiss, Germany
11.30-11.50	"3D imaging using different sources" 3	Erik Mejdal Lauridsen, DTU Energy Conversion, Denmark
11.50-12.10	Break Session on "Metrology of Computed Tomography"	
12.10-12.50	Keynote "CT for dimensional metrology" 4	Ralf Christoph, Werth Germany
12.50-13.10	"Practical solutions to the measurement of micro 5 structure resolution"	Simone Carmignato, Padova University, Italy
13.10-14.20	Lunch Session on "Industrial applications"	
14.20-14.40	"CIA-CT inter laboratory comparison on industrial 6 computed tomography"	Erik Larsen, IPU, Denmark
14.40-15.10	"Applications of Computed Tomography in 7 Industrial Production"	David Bate, Nikon Metrology, UK and Wenjuan Sun, NPL, UK Martin Simon, Wenzel, Germany
15.10-15.30	"Applications of CT in the manufacturing industry" 8	
15.30-15.40	Break	
15.40-16.00	"Tree D Furniture – CT in wood" 9	Jørgen Rheinlænder, InnospeXion, Denmark
16.00-16.20	"Computed Tomography solutions in the food 10 industry"	Lars Bager Chistensen, Teknologisk/DMRI, Denmark
16.20-16.30	Closure	